

ON Semiconductor®

FDMC3612GenN-Channel Power Trench[®]MOSFET100 V, 12 A, 110 mΩSemi

Features

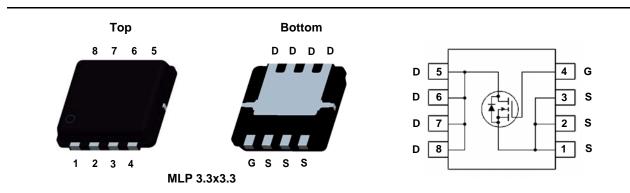
- Max $r_{DS(on)}$ = 110 m Ω at V_{GS} = 10 V, I_D = 3.3 A
- Max $r_{DS(on)}$ = 122 m Ω at V_{GS} = 6 V, I_D = 3.0 A
- Low Profile 1 mm max in Power 33
- 100% UIL Tested
- RoHS Compliant

General Description

This N-Channel MOSFET is produced using ON Semiconductor's advanced Power Trench[®] process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Applications

- DC DC Conversion
- PSE Switch



MOSFET Maximum Ratings T_C = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V _{DS}	Drain to Source Voltage			100	V	
V _{GS}	Gate to Source Voltage			±20	V	
	Drain Current -Continuous (Package limited)	T _C = 25 °C		16	12 A	
	-Continuous (Silicon limited)	T _C = 25 °C		12		
ID	-Continuous	T _A = 25 °C	(Note 1a)	3.3		
	-Pulsed			15		
E _{AS}	Single Pulse Avalanche Energy (Note 3)		(Note 3)	32	mJ	
P _D	Power Dissipation $T_{\rm C} = 25$			35	14/	
	Power Dissipation	T _A = 25 °C	(Note 1a)	2.3	W	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to + 150	°C		

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	3.5	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient (Note 1a) 53	0/11

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC3612	FDMC3612	Power 33	13"	12 mm	3000 units

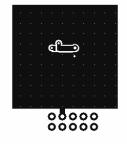
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units	
Off Chara	acteristics						
BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0 V	100			V	
ΔBV_{DSS} ΔT_J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$, referenced to 25 °C		109		mV/°C	
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 80 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μA	
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA	
On Chara	octeristics						
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250 \ \mu A$	2.0	2.5	4.0	V	
$\Delta V_{GS(th)}$ ΔT_J	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C		-7		mV/°C	
		$V_{GS} = 10 \text{ V}, I_D = 3.3 \text{ A}$		92	110	mΩ	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, \ I_D = 3.0 \text{ A}$		98	122		
		$V_{GS} = 10 \text{ V}, \ I_D = 3.3 \text{ A}, \ T_J = 125 \text{ °C}$		177	212		
9 _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, \ \text{I}_{D} = 3.3 \text{ A}$		13		S	
Dynamic	Characteristics						
C _{iss}	Input Capacitance	V 50.V.V 0.V		662	880	pF	
C _{oss}	Output Capacitance	── V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz		40	55	pF	
C _{rss}	Reverse Transfer Capacitance			23	35	pF	
R _g	Gate Resistance			1.3		Ω	
Switchind	g Characteristics						
t _{d(on)}	Turn-On Delay Time			7.4	15	ns	
t _r	Rise Time	V _{DD} = 50 V, I _D = 3.3 A,		2.8	10	ns	
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		19	34	ns	
t _f	Fall Time			2	10	ns	
Q _{g(TOT)}	Total Gate Charge	$V_{GS} = 0 V \text{ to } 10 V$ $V_{GS} = 0 V \text{ to } 5 V$ $V_{DD} = 50 V,$ $I_{D} = 3.3 A$		14.4	21	nC	
Q _{g(TOT)}	Total Gate Charge	$V_{GS} = 0 V \text{ to } 5 V$ $V_{DD} = 50 V,$		7.9	12	nC	
Q _{gs}	Total Gate Charge	I _D = 3.3 A		2.3		nC	
Q _{gd}	Gate to Drain "Miller" Charge			3.7		nC	
Drain-Sou	urce Diode Characteristics						
		$V_{GS} = 0 V, I_S = 3.3 A$ (Note 2)		0.88	1.2		
V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_S = 2 A$ (Note 2)		0.77	1.2	V	
				1	+	-	

Q _{rr}
NOTES:

t_{rr}

1. $R_{0,L}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{0,LC}$ is guaranteed by design while $R_{0,CA}$ is determined by the user's board design.

 $I_F = 3.3 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$



Reverse Recovery Time

Reverse Recovery Charge

a) 53 °C/W when mounted on a 1 in² pad of 2 oz copper



b) 125 °C/W when mounted on a minimum pad of 2 oz copper

34

37

55

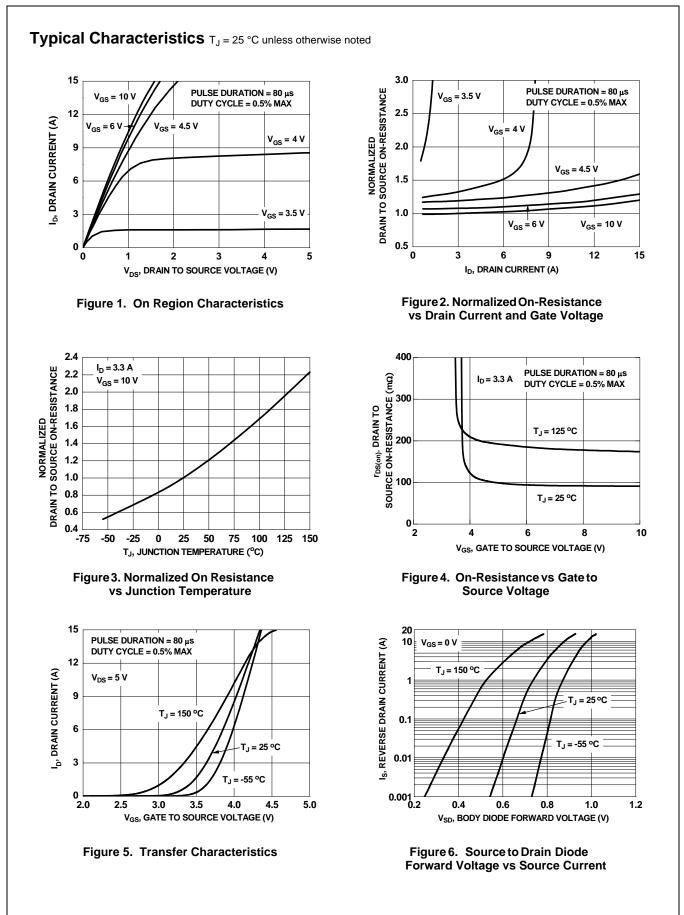
60

ns

nC

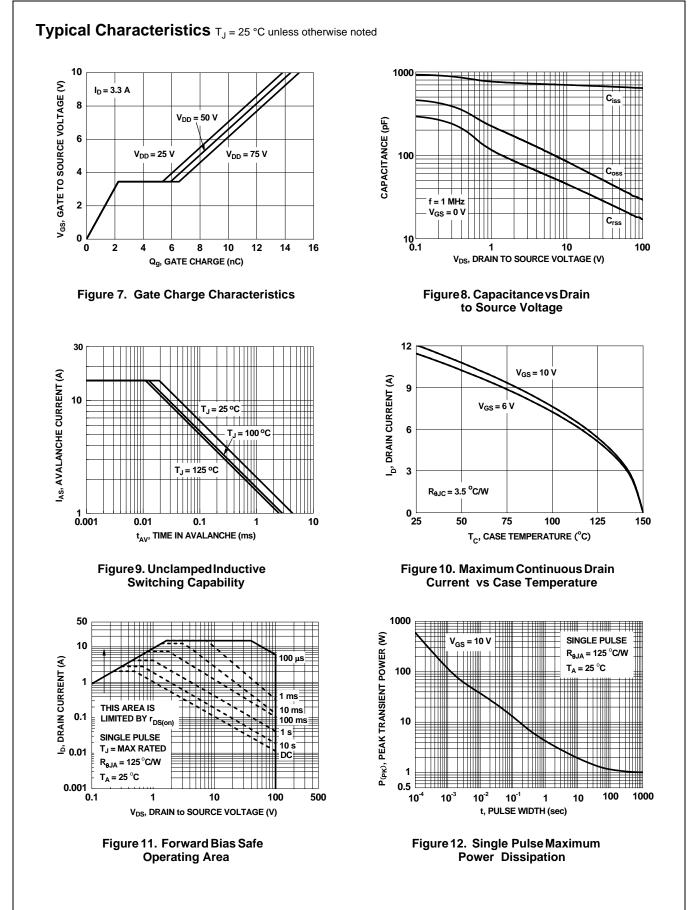
2. Pulse Test: Pulse Width < 300 $\mu s,$ Duty cycle < 2.0%.

3. Starting T_J = 25 °C; N-ch: L = 1 mH, I_{AS} = 8 A, V_{DD} = 90 V, V_{GS} = 10 V.



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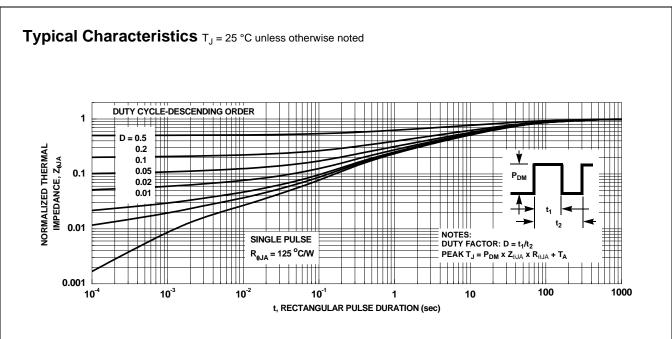


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

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